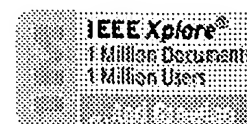


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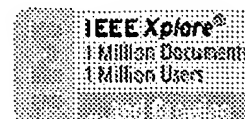
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Yu, H.Y.; Lim, H.F.; Chen, J.H.; Li, M.F.; Zhu, C.X.; Kwong, D.-L.; Tung, C.H.;
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